

<div> <div>Notice of References Cited</div> </div>	<div> <div>Application/Control No.</div> <div>10/064,972</div> </div>	<div> <div>Applicant(s)/Patent Under Reexamination</div> <div>TENG ET AL.</div> </div>	
	<div> <div>Examiner</div> <div>YOUNG T. TSE</div> </div>	<div> <div>Art Unit</div> <div>2637</div> </div>	<div> <div>Page 1 of 1</div> </div>

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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